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# 8-Mbit (512 K × 16) Static RAM

### Features

- Temperature ranges □ -40 °C to 125 °C
- High speed □ t<sub>AA</sub> = 15 ns
- Low active power □ I<sub>CC</sub> = 120 mA at 67 MHz
- Low CMOS standby power □ I<sub>SB2</sub> = 20 mA
- 2.0-V data retention
- Automatic power-down when deselected
- Transistor-transistor logic (TTL)-compatible inputs and outputs
- Easy memory expansion with CE and OE features
- Available in Pb-free 44-pin thin small outline package (TSOP) II.

### **Functional Description**

The CG7480AT is a high performance CMOS Static RAM organized as 512 K words by 16 bits.

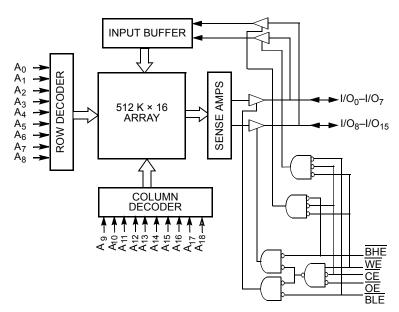
To write to the device, take Chip Enable  $\overline{(CE)}$  and Write Enable  $\overline{(WE)}$  inputs LOW. If Byte LOW Enable (BLE) is LOW, then data from I/O pins (I/O<sub>0</sub>–I/O<sub>7</sub>), is written into the location specified on the address pins (A<sub>0</sub>–A<sub>18</sub>). If Byte HIGH Enable (BHE) is LOW, then data from I/O pins (I/O<sub>8</sub>–I/O<sub>15</sub>) is written into the location specified on the address pins (A<sub>0</sub>–A<sub>18</sub>).

To read from the device, take Chip Enable ( $\overline{\text{CE}}$ ) and Output Enable ( $\overline{\text{OE}}$ ) LOW while forcing the Write Enable (WE) HIGH. If Byte LOW Enable (BLE) is LOW, then data from the memory location specified by the address pins appears on I/O<sub>0</sub>–I/O<sub>7</sub>. If Byte HIGH Enable (BHE) is LOW, then data from memory appears on I/O<sub>8</sub> to I/O<sub>15</sub>. See the Truth Table on page 11 for a complete description of read and write modes.

The input/output pins  $(I/O_0-I/O_{15})$  are placed in a high-impedance state when the device is deselected (CE HIGH), the outputs are disabled (OE HIGH), the BHE and BLE are disabled (BHE, BLE HIGH), or a write operation (CE LOW, and WE LOW) is in progress.

The CG7480AT is available in a 44-pin TSOP II package with center power and ground (revolutionary) pinout.

### Logic Block Diagram



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## CG7480AT

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## **Pin Configuration**

Figure 1. 44-pin TSOP II pinout (Top View) <sup>[1]</sup>

A <sub>0</sub> E	1	44		A <sub>17</sub>
AĭĒ	2	43	٦	A <sub>16</sub>
A <sub>2</sub>	3	42		A <sub>15</sub>
A <sub>2</sub>	4	41		OE
A <sub>4</sub>	5	40		BHE
CE	6	39		BLE
I/Q₀ ⊑	7	38		I/O15
I/O <sub>I</sub> 🗆	8	37		I/O14
I/O₂ ⊑	9	36		I/O13
I/O₃ □	10	35	Ц	I/Ora
V <sub>CC</sub> E	11	34		VSS
VSS	12	33	Ц	Vcc
I/O <sub>4</sub>	13	32	Ц	$I/O_{11}$
I/O <sub>5</sub> ⊑	14	31	Π	I/O <sub>10</sub>
I/Q <sub>6</sub> ⊑	15	30	2	I/O
1/07	16	29	Ц	Ï/Q8
WE	17	28		A <sub>18</sub>
A <sub>5</sub> 🗆	18	27	2	A <sub>14</sub>
A <sub>6</sub> E	19	26	Ц	A <sub>13</sub>
A7	20	25	Ц	A <sub>12</sub>
A <sub>8</sub>	21	24	H	A <sub>11</sub>
A <sub>9</sub>	22	23	μ	A <sub>10</sub>

### **Selection Guide**

Description	-15	Unit
Maximum access time	15	ns
Maximum operating current	120	mA
Maximum CMOS standby current	20	mA



### **Maximum Ratings**

Exceeding the maximum ratings may shorten the useful life of the device. These user guidelines are not tested.

Storage temperature65 °C to +150 °C	°C
Ambient temperature with power applied55 °C to +125 °C	S°C
Supply voltage on $V_{CC}$ to relative GND $^{[2]}$ 0.5 V to +4.6 V	6 V
DC voltage applied to outputs in high-Z state $^{[2]}$ 0.3 V to V_{CC} + 0.3 V	3 V

DC input voltage <sup>[2]</sup>	-0.3 V to V <sub>CC</sub> + 0.3 V
Current into outputs (LOW)	
Static discharge voltage (per MIL-STD-883, Method 3015)	>2001 V
Latch-up current	>200 mA

## **Operating Range**

Device	Ambient Temperature	V <sub>cc</sub>	Speed
CG7480AT	–40 °C to +125 °C	$3.3~V\pm0.3~V$	15 ns

### **DC Electrical Characteristics**

Over the Operating Range

Parameter	Description	Test Conditions	-	Unit	
Farameter	Description	Test conditions	Min	Max	Unit
V <sub>OH</sub>	Output HIGH voltage	Min V <sub>CC</sub> , $I_{OH}$ = -4.0 mA	2.4	-	V
V <sub>OL</sub>	Output LOW voltage	Min V <sub>CC</sub> , I <sub>OL</sub> = 8.0 mA	-	0.4	V
V <sub>IH</sub> <sup>[2]</sup>	Input HIGH voltage		2.0	V <sub>CC</sub> + 0.3	V
V <sub>IL</sub> [2]	Input LOW voltage		-0.3	0.8	V
I <sub>IX</sub>	Input leakage current	$GND \leq V_{IN} \leq V_{CC}$	-5	+5	μA
I <sub>OZ</sub>	Output leakage current	GND $\leq$ V <sub>OUT</sub> $\leq$ V <sub>CC</sub> , Output Disabled	-5	+5	μA
I <sub>CC</sub>	$V_{CC}$ operating supply current	Max V <sub>CC</sub> , f = $f_{MAX} = 1/t_{RC}$	-	120	mA
I <sub>SB1</sub>	Automatic CE power down current – TTL inputs	$\begin{array}{l} \text{Max } V_{CC}, \ \overline{CE} \geq V_{IH}, \\ V_{IN} \geq V_{IH} \text{ or } V_{IN} \leq V_{IL}, \ f = f_{MAX} \end{array}$	-	60	mA
I <sub>SB2</sub>	Automatic CE Power Down Current – CMOS Inputs	$\begin{array}{l} \text{Max V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V}, \\ \text{V}_{\text{IN}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V} \text{ or } \text{V}_{\text{IN}} \leq 0.3 \text{ V}, \text{ f} = 0 \end{array}$	-	20	mA



### Capacitance

Parameter <sup>[3]</sup>	Description	Test Conditions	Мах	Unit
C <sub>IN</sub>	Input capacitance	T <sub>A</sub> = 25 °C, f = 1 MHz, V <sub>CC</sub> = 3.3 V	12	рF
C <sub>OUT</sub>	I/O capacitance		12	рF

### **Thermal Resistance**

Parameter <sup>[3]</sup>	Description	Test Conditions	TSOP II Package	Unit
$\Theta_{JA}$	Thermal resistance (junction to ambient)	Still air, soldered on a $3 \times 4.5$ inch, four-layer printed circuit board	51.43	°C/W
Θ <sup>JC</sup>	Thermal resistance (junction to case)		15.8	°C/W

### **AC Test Loads and Waveforms**

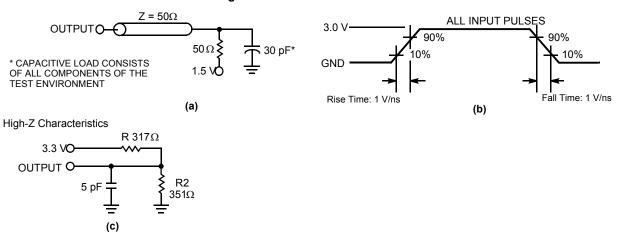


Figure 2. AC Test Loads and Waveforms <sup>[4]</sup>

#### Notes

- Tested initially and after any design or process changes that may affect these parameters.
  AC characteristics (except High-Z) are tested using the load conditions shown in Figure 2 (a). High-Z characteristics are tested for all speeds using the test load shown in Figure 2 (c).



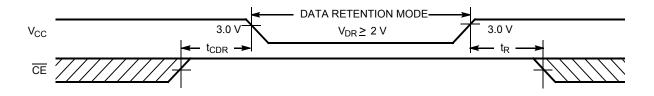
### **Data Retention Characteristics**

Over the Operating Range

Parameter	Description	Conditions <sup>[5]</sup>	Min	Max	Unit
V <sub>DR</sub>	V <sub>CC</sub> for Data Retention		2.0	-	V
I <sub>CCDR</sub>	Data Retention Current	$V_{CC} = V_{DR} = 2.0 \text{ V}, \overline{CE} \ge V_{CC} - 0.3 \text{ V},$ $V_{IN} \ge V_{CC} - 0.3 \text{ V} \text{ or } V_{IN} \le 0.3 \text{ V}$	-	20	mA
t <sub>CDR</sub> <sup>[6]</sup>	Chip Deselect to Data Retention Time	$V_{IN} \ge V_{CC} - 0.3 V \text{ or } V_{IN} \le 0.3 V$	0	_	ns
t <sub>R</sub> [6]	Operation Recovery Time		t <sub>RC</sub>	-	ns

### **Data Retention Waveform**





#### Notes

5. No inputs may exceed  $V_{CC}$  + 0.3 V. 6. Full device operation requires linear  $V_{CC}$  ramp from  $V_{DR}$  to  $V_{CC}(min) \ge 50 \ \mu s$  or stable at  $V_{CC}(min) \ge 50 \ \mu s$ .



### **AC Switching Characteristics**

Over the Operating Range

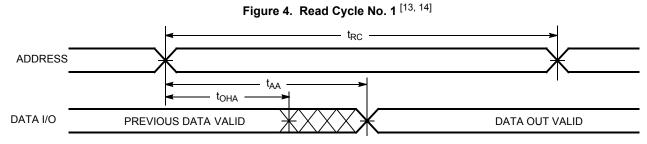
Parameter [7]	Description	-	15	Unit
Parameter 11	Description	Min	Мах	
Read Cycle				•
t <sub>power</sub> <sup>[8]</sup>	V <sub>CC</sub> (typical) to the First Access	100	-	μS
t <sub>RC</sub>	Read Cycle Time	15	_	ns
t <sub>AA</sub>	Address to Data Valid	-	15	ns
t <sub>OHA</sub>	Data Hold from Address Change	3	-	ns
t <sub>ACE</sub>	CE LOW to Data Valid	-	15	ns
t <sub>DOE</sub>	OE LOW to Data Valid	-	7	ns
t <sub>LZOE</sub>	OE LOW to Low-Z	0	_	ns
t <sub>HZOE</sub>	OE HIGH to High-Z <sup>[9, 10]</sup>	-	7	ns
t <sub>LZCE</sub>	CE LOW to Low-Z <sup>[10]</sup>	3	_	ns
t <sub>HZCE</sub>	CE HIGH to High-Z <sup>[9, 10]</sup>	-	6	ns
t <sub>PU</sub>	CE LOW to Power Up	0	_	ns
t <sub>PD</sub>	CE HIGH to Power Down	-	15	ns
t <sub>DBE</sub>	Byte Enable to Data Valid	-	7	ns
t <sub>LZBE</sub>	Byte Enable to Low-Z	0	_	ns
t <sub>HZBE</sub>	Byte Disable to High-Z	-	7	ns
Write Cycle [11	, 12]			•
t <sub>WC</sub>	Write Cycle Time	15	_	ns
t <sub>SCE</sub>	CE LOW to Write End	10	_	ns
t <sub>AW</sub>	Address Setup to Write End	10	_	ns
t <sub>HA</sub>	Address Hold from Write End	0	_	ns
t <sub>SA</sub>	Address Setup to Write Start	0	_	ns
t <sub>PWE</sub>	WE Pulse Width	10	_	ns
t <sub>SD</sub>	Data Setup to Write End	7	-	ns
t <sub>HD</sub>	Data Hold from Write End	0	-	ns
t <sub>LZWE</sub>	WE HIGH to Low-Z <sup>[10]</sup>	3	-	ns
t <sub>HZWE</sub>	WE LOW to High-Z <sup>[9, 10]</sup>	-	7	ns
t <sub>BW</sub>	Byte Enable to End of Write	10	-	ns

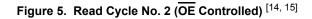
Notes

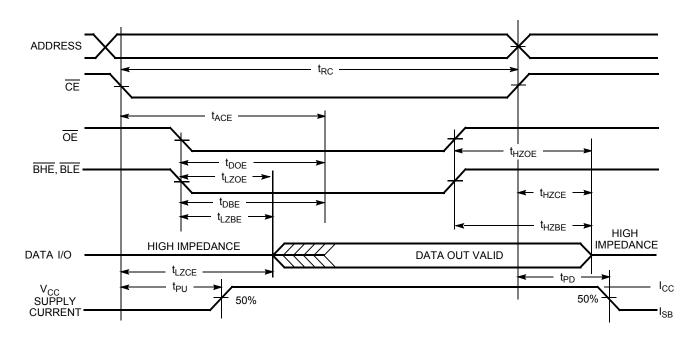
- 7. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V.
  8. t<sub>POWER</sub> gives the minimum amount of time that the power supply must be at typical V<sub>CC</sub> values until the first memory access can be performed.
  9. t<sub>HZOE</sub>, t<sub>HZEE</sub>, t<sub>HZBE</sub> and t<sub>HZWE</sub> are specified with a load capacitance of 5 pF as in part (d) of Figure 2 on page 5.Transition is measured when the outputs enter a high impedance state.
- 10. At any temperature and voltage condition, t<sub>HZCE</sub> is less than t<sub>LZCE</sub>, t<sub>HZDE</sub> is less than t<sub>LZCE</sub>, t<sub>HZDE</sub> is less than t<sub>LZDE</sub>, and t<sub>HZWE</sub> is less than t<sub>LZWE</sub> for any device.
  11. The internal write time of the memory is defined by the overlap of CE LOW, and WE LOW. CE and WE must be LOW to initiate a write, and the transition of either of these signals can terminate the write. The input data setup and hold timing must refer to the leading edge of the signal that terminates the write.
  12. The minimum write cycle time for Write Cycle No. 3 (WE controlled, OE LOW) is the sum of t<sub>HZWE</sub> and t<sub>SD</sub>.



**Switching Waveforms** 







#### Notes

- 13. Device is continuously selected.  $\overline{OE}$ ,  $\overline{CE} = V_{IL}$ ,  $\overline{BHE}$ ,  $\overline{BLE}$ , or both =  $V_{IL}$ .
- 14. WE is HIGH for Read cycle.

15. Address valid before or coincident with  $\overline{CE}$  transition LOW.



### Switching Waveforms(continued)

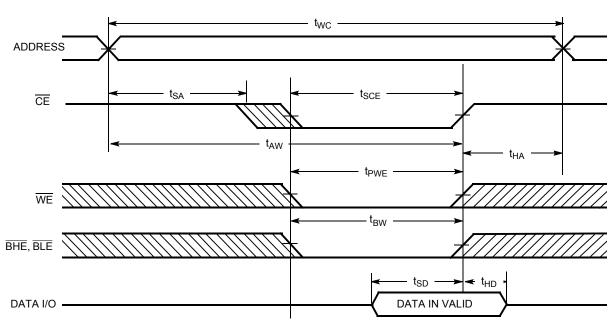
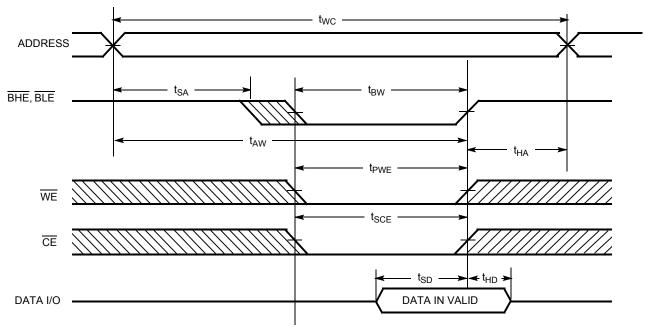


Figure 6. Write Cycle No. 1 (CE Controlled) <sup>[16, 17]</sup>

Figure 7. Write Cycle No. 2 (BLE or BHE Controlled)



#### Notes

16. Data I/O is high-impedance if OE, or BHE, BLE, or both = V<sub>IH</sub>. 17. If CE goes HIGH simultaneously with WE going HIGH, the output remains in a high-impedance state.



### Switching Waveforms(continued)

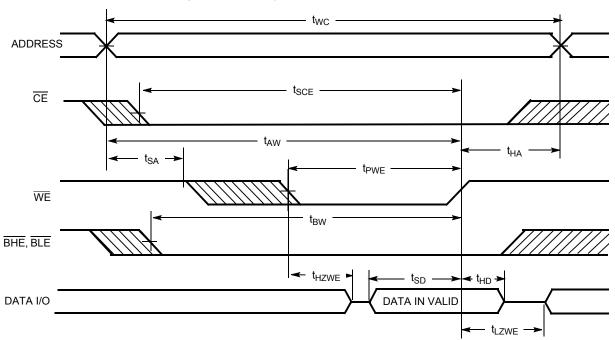


Figure 8. Write Cycle No. 3 (WE Controlled, OE LOW) <sup>[18]</sup>



## Truth Table

CE	OE	WE	BLE	BHE	I/O <sub>0</sub> –I/O <sub>7</sub>	I/O <sub>8</sub> –I/O <sub>15</sub>	Mode	Power
Н	Х	Х	Х	Х	High-Z	High-Z	Power Down	Standby (I <sub>SB</sub> )
L	L	Н	L	L	Data Out	Data Out	Read All Bits	Active (I <sub>CC</sub> )
L	L	Н	L	Н	Data Out	High-Z	Read Lower Bits Only	Active (I <sub>CC</sub> )
L	L	Н	Н	L	High-Z	Data Out	Read Upper Bits Only	Active (I <sub>CC</sub> )
L	Х	L	L	L	Data In	Data In	Write All Bits	Active (I <sub>CC</sub> )
L	Х	L	L	Н	Data In	High-Z	Write Lower Bits Only	Active (I <sub>CC</sub> )
L	Х	L	Н	L	High-Z	Data In	Write Upper Bits Only	Active (I <sub>CC</sub> )
L	Н	Н	Х	Х	High-Z	High-Z	Selected, Outputs Disabled	Active (I <sub>CC</sub> )
L	Х	Х	Н	Н	High-Z	High-Z	Selected, Outputs Disabled	Active (I <sub>CC</sub> )



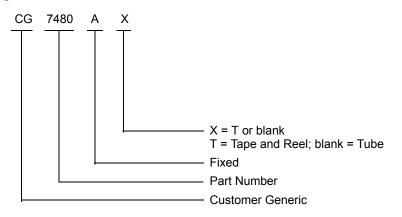
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Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
15	CG7480AT	51-85087	44-pin TSOP II (Pb-free)	Industrial

Contact your local Cypress sales representative for availability of these parts.

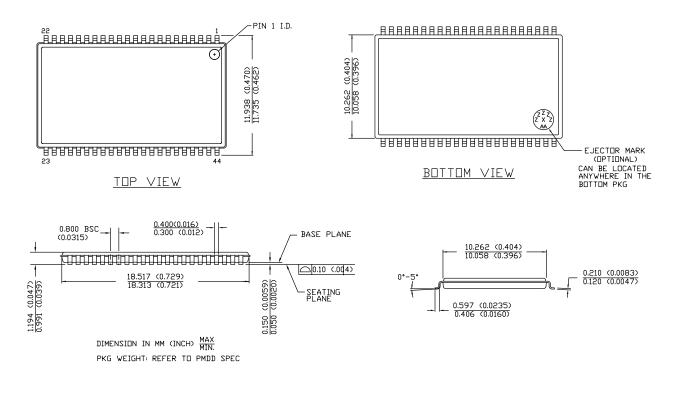
#### **Ordering Code Definitions**





### **Package Diagrams**

Figure 9. 44-pin TSOP II Package Outline, 51-85087



51-85087 \*E



### Acronyms

Acronym	Description
CE	Chip Enable
CMOS	Complementary Metal Oxide Semiconductor
I/O	Input/Output
OE	Output Enable
SRAM	Static Random Access Memory
SOJ	Small Outline J-lead
TSOP	Thin Small Outline Package

### **Document Conventions**

### **Units of Measure**

Symbol	Unit of Measure				
°C	degree Celsius				
MHz	megahertz				
μA	microampere				
mA	milliampere				
mV	millivolt				
mW	milliwatt				
ns	nanosecond				
ppm	parts per million				
pF	picofarad				
V	volt				
W	watt				



## **Document History Page**

Document Title: CG7480AT, 8-Mbit (512 K × 16) Static RAM Document Number: 001-73191				
Revision	ECN	Orig. of Change	Submission Date	Description of Change
**	3389929	TAVA	01/18/2012	New data sheet.
*A	4333695	VINI	04/04/2014	Updated Switching Waveforms: Added Note 18 and referred the same note in Figure 8. Updated Package Diagrams: spec 51-85087 – Changed revision from *D to *E. Updated in new template. Completing Sunset Review.



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